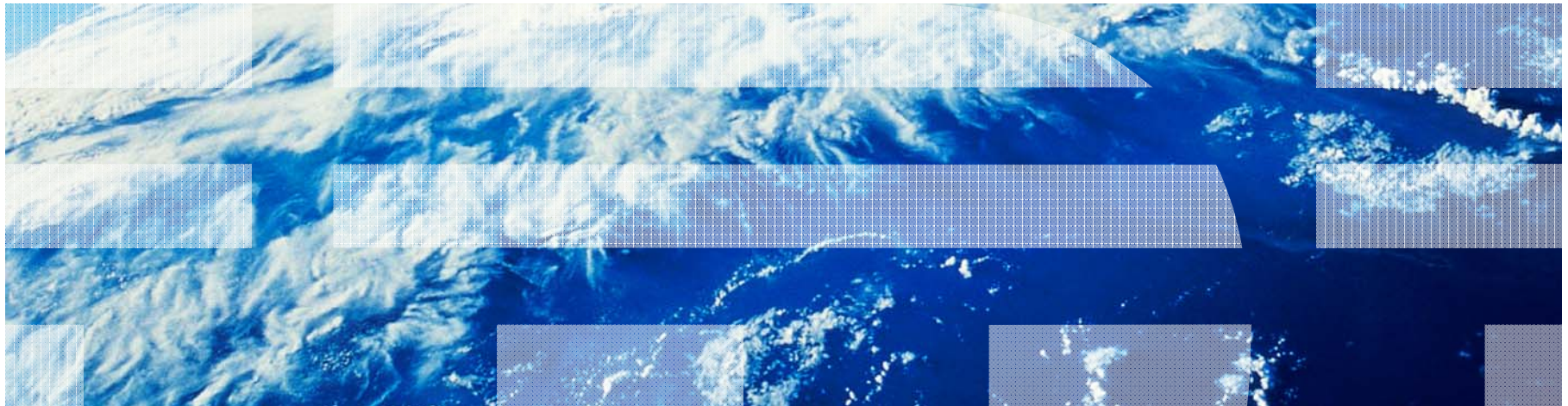




# Technology Roadmap Comparisons for TAPE, HDD, and NAND Flash: Implications for Data Storage Applications



## Outline

- **Business as Usual Areal Density Increase → 40% per Year**
- **Premise: The annual rate of areal density increases for TAPE will likely exceed the annual rate of areal density increases for NAND and HDD**
  - TAPE bit cell is large and paths for scaling to higher bit densities exist
  - NAND bit cells and HDD Patterned Media bit cells are approaching nanoscale issues in minimum feature lithography requirements
  - NAND bit endurance or bit retention and HDD bit stability are approaching kT fluctuation issues driven by the small volume of the bit cells at high areal densities ( < 1900 nm<sup>2</sup> bit cell area)
- **Comment: TAPE, NAND, and HDD will continue to offer complementary storage solutions**
- **Implications for TAPE: TAPE volumetric density will increase, allowing for new tape opportunities in a more cost sensitive storage environment**
- **A Possible Annual Areal Density Growth Scenarios**
  - ~ 20% for HDD
  - ~ 20% for NAND Flash
  - > 40% for TAPE

---

## Outline NEW

- **Areal density landscape for TAPE, HDD, NAND**
- **Bit cells**
- **Lithography and / or bit cell definition**
- **TAPE , NAND, HDD landscapes**
- **Areal density increase scenarios for the next 4 year period**
- **Conclusions**

## Storage Component Landscape

### ▪ Three Components

- HDD ~ 500 GB capacity 630 million units/yr (large commodity base)
- NAND Chip ~ 4 GB capacity 4 billion units/yr (large commodity base)
- LTO Tape Cartridge ~ 800 GB capacity 24 million units/yr (**no commodity base**)

### ▪ The Industries

	2010	2011
HDD Revenue	\$33.5 B	\$33.5 B
HDD PB Shipped	330000 PB	330000 PB
HDD \$/GB Shipped	\$0.10/GB	\$0.10/GB
NAND Revenue	\$18.5 B	\$21.5 B
NAND PB Shipped	10,400 PB	18,600 PB
NAND \$/GB	\$1.77/GB	\$1.16/GB
TAPE LTO Cartridge Revenue	\$0.7 B	\$0.7B
TAPE LTO Cartridge PB Shipped	15,300 PB	17,800 PB
TAPE LTO Cartridge \$/GB	\$0.046/GB	\$0.038/GB



***Thailand Floods  
Industry Consolidation***



***Transition from 30 nm  
to 20 nm Lithography***



***Introduction of LTO5  
Tape Generation***

## Areal Density Overview (a moving target -- concentrate on YE 2011 values)

- **HDD (20% - 30%) / Year**

- YE 2009      530 Gbit/in<sup>2</sup>
- YE 2010      635 Gbit/in<sup>2</sup>
- Mid 2011     750 Gbit/in<sup>2</sup>



- **HDD (3.5" Platter)**

- 750 GB → 1.0 TB

- **TAPE (40% / Year)**

- Mid 2008     1.0 Gbit/in<sup>2</sup>
- Mid 2010     1.2 Gbit/in<sup>2</sup>
- Mid 2011     3.2 Gbit/in<sup>2</sup>



- **TAPE (LTO like Cartridge)**

- 1.5 TB → 4.0 TB

- **NAND (40% / Year)**

- Mid 2008     200 Gbit/in<sup>2</sup>
- Mid 2010     330 Gbit/in<sup>2</sup>
- Mid 2011     550 Gbit/in<sup>2</sup>



- **NAND (Chip )**

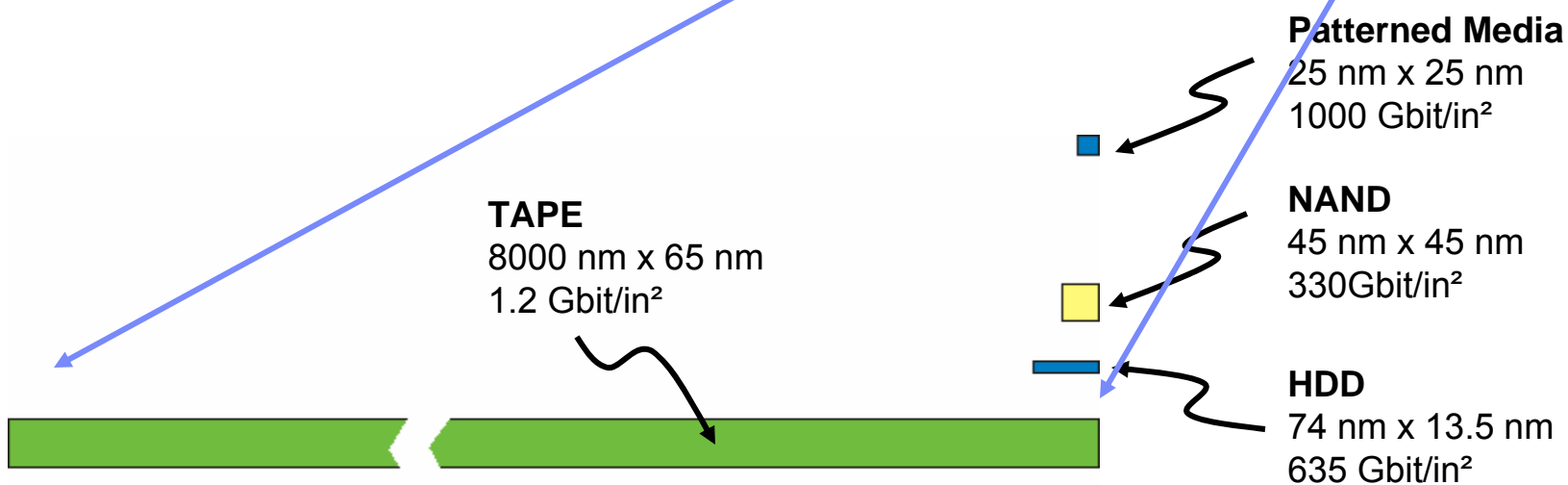
- 8 GB → 8 GB with 40% less area)

## Storage Bit Cells and Extendability

- **Scaled Bit Cells**

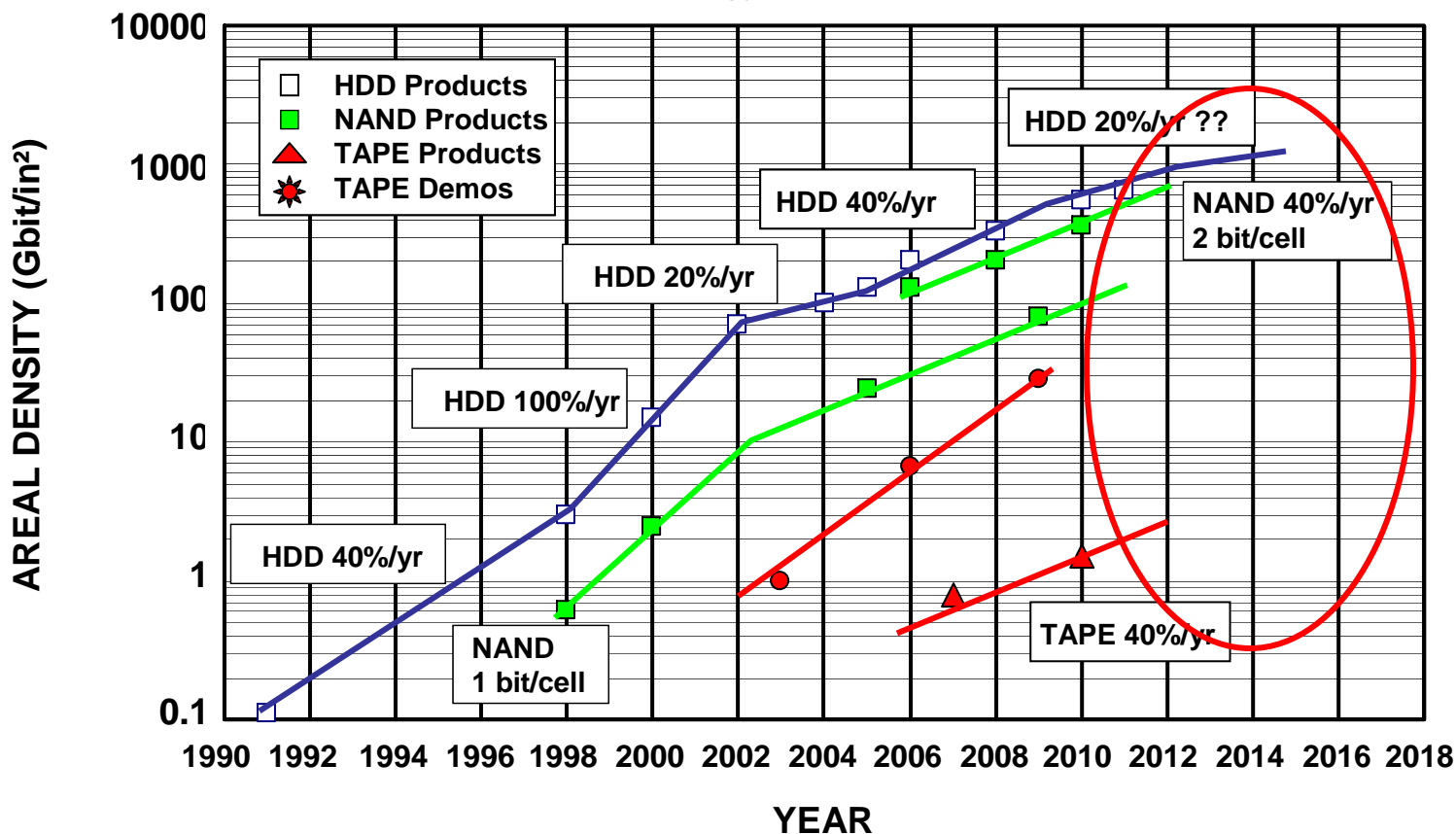


- **Magnified View of Scaled Bit Cells**



## Storage Device Density Landscape – A History

- **HDD**
  - 1998 – 2002 density increases at 100% per year (GMR)
- **TAPE**
  - Sustained 40% density increases with demos showing potential for greater increases
- **NAND**
  - 2005 -- transition to 2 bit/cell technology (endurance sacrifice)



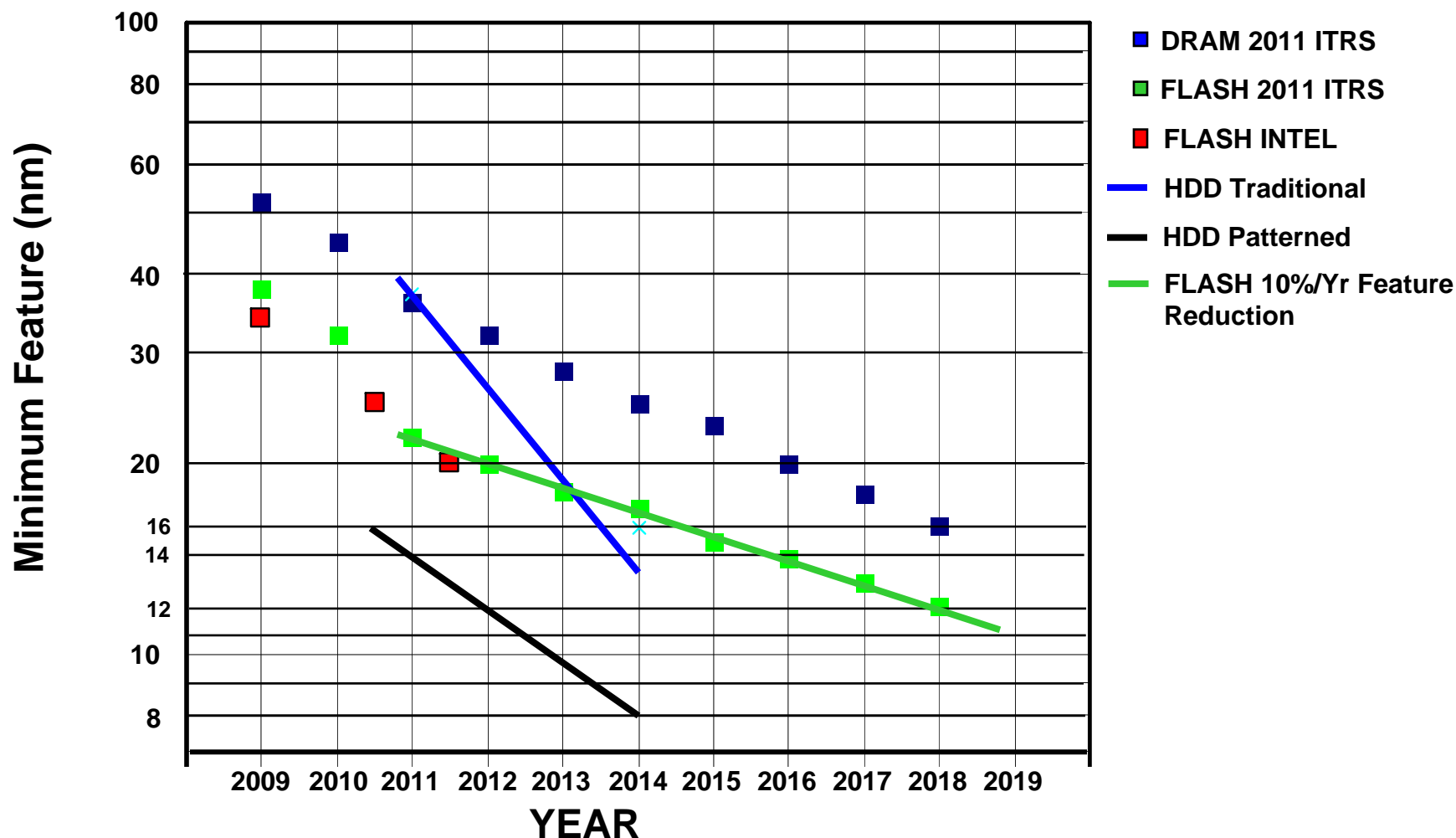
## Bit Cell Implications for 40% Annual Areal Density Increases

<b>TECHNOLOGY METRIC</b>	<b>2010</b>	<b>2014 (40% / Yr)</b>
<b><u>TAPE</u></b>		
-- Areal Density	1.2 Gbit / in <sup>2</sup>	4.8 Gbit / in <sup>2</sup>
-- Bit Length	8000 nm	2000 nm
-- Bit Width	65 nm	65 nm
-- Minimum Feature	4000 nm	1000 nm
<b><u>HDD</u></b>		
-- Areal Density	635 Gbit / in <sup>2</sup>	2500 Gbit / in <sup>2</sup>
-- Bit Length	74 nm	19 nm
-- Bit Width	13.5 nm	13.5 nm
-- Minimum Feature	37 nm	10 nm
<b><u>NAND Flash</u></b>		
-- Areal Density	330 Gbit / in <sup>2</sup>	1300 Gbit / in <sup>2</sup>
-- Bit Length	45 nm	20 nm
-- Bit Width	45 nm	20 nm
-- Minimum Feature	25 nm	12 nm



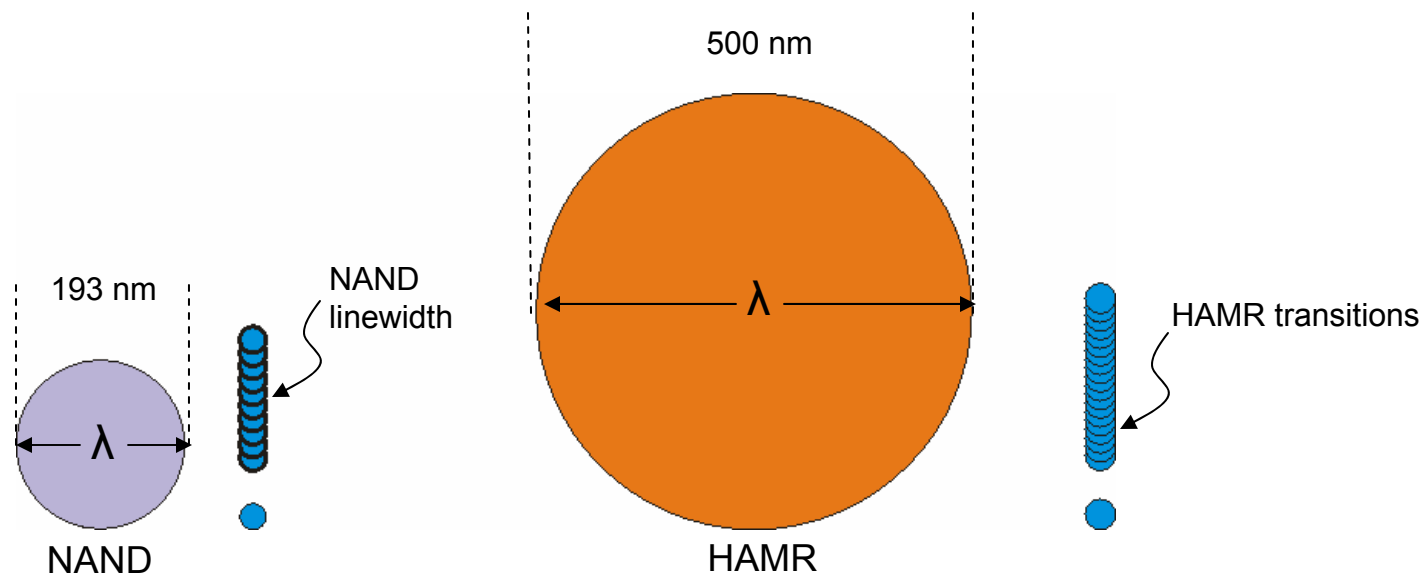
## Lithography Roadmaps

- Minimum feature typically reduced by 12% per year
- Intel/Micron has consistently exceeded ITRS goals



## NAND and HAMR Optics -- Today

- **NAND uses 193 nm wavelength light to resolve 20 nm features**
  - Phase shift masking
  - Immersion lithography
  - Double exposure at 2X line pitch
  - Chemically amplified resists
  
- **HAMR uses ~ 500 nm wavelength light to resolve 100 nm features today and 35 nm features for 2 Tbit/in<sup>2</sup> in the 2014 time frame**
  - Waveguide propagation
  - Waveguide termination with aperture feature (minimum feature)
  - Near field thermal effects
  - Media layer heat sinking




## TAPE Landscape – 1.5 TB LTO-5 Tape Cartridge

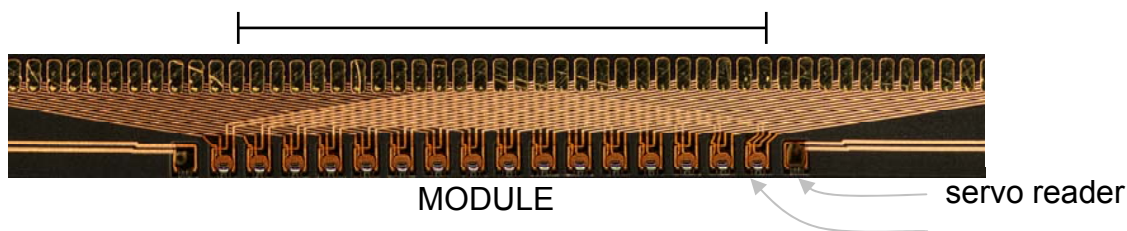
- **Tape data storage capacity achieved using 840 m tape length, 12.8 mm wide, and 6.4  $\mu\text{m}$  thick**

- Tape surface area in a cartridge ( $10.5 \times 10^6 \text{ mm}^2$ ) is equivalent to 148 12" Si wafers or 1736 3.5" disk surfaces
- Some surface area utilized for edge guards, servo tracks, leading and trailing tape end lengths leading to surface storage efficiencies of  $\sim 65\%$

- **1.5 TB LTO-5 Cartridge Details**

- Areal Density (Maximum)  $\rightarrow 1.2 \text{ Gbit/in}^2$  ( $0.72 \text{ Gbit/in}^2$  average density)
- Total Tracks  $\rightarrow 1280$
- Trackwidth  $\rightarrow 8100 \text{ nm}$  or  $8.1 \mu\text{m}$
- Bit Length  $\rightarrow 65 \text{ nm}$  (Bit Aspect Ratio = 125!!!)
- TPI, BPI  $\rightarrow 3.1 \text{ KTPI}, 385 \text{ KBPI}$
- Read Width/Minimum Feature  $\rightarrow \sim \frac{1}{2}$  Trackwidth,  $\sim 4.0 \mu\text{m}$  
- Memory Cell Area ( $F^2$ )  $\rightarrow \sim 0.03F^2$  !!!

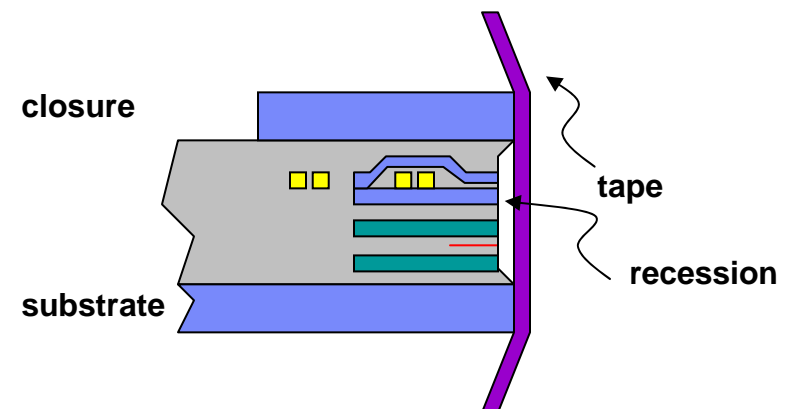
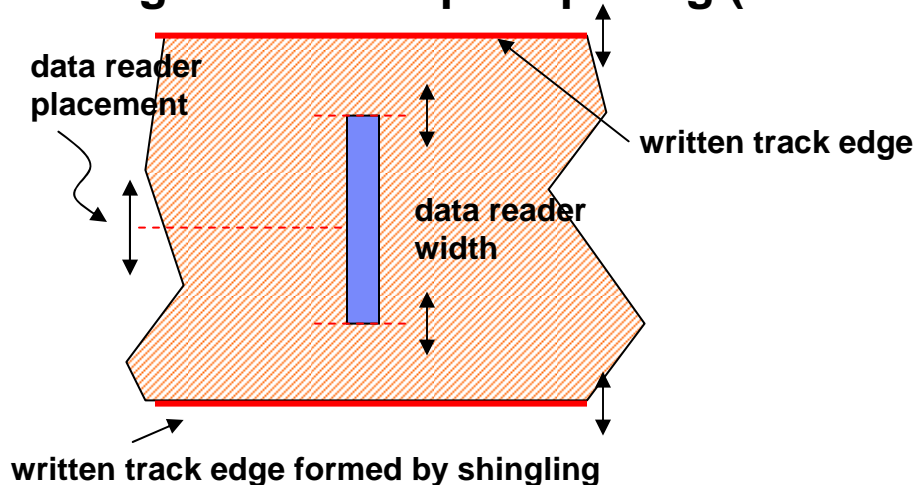
- **The Head – 16 tracks, 2 servo elements**



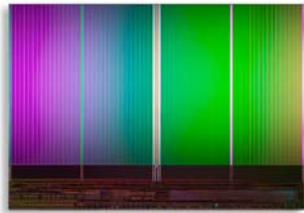
- **Media** -- Recording demonstrations suggest that tape areal densities in excess of 25 Gb/in<sup>2</sup> can be supported (**20X**). SNR is the issue
- **Head** -- The transition to GMR based sensors provides path for maintaining amplitude as trackwidth decreases and present trackwidths and MR widths in the 4 um range are **200X** larger than present IC minimum features (20 nm); lithography limits are non issues
- **Bit Cell** -- The volume of the bit cell is large so kT fluctuations are minimal and bits are stable. TAPE heads use *proven* HDD technology of 12 years ago.

## CAVEATS

- **Flexible media and track following**
- **Large “head – tape” spacing (i.e. recession changes during head lifetime)**



## 8 GB 20 nm IM Flash



12.5 mm

- Chip Area → 118 mm<sup>2</sup> (12.5 mm x 9.5 mm)
- Active Memory Area → 71 mm<sup>2</sup> (63% efficiency)
- Minimum Feature (F) → 20 nm
- Memory Cell Area → 1109 nm<sup>2</sup>
- Memory Cell Area → 2.8 F<sup>2</sup> (not 2 F<sup>2</sup> !!!)
- Local Areal Density → 560 Gb/in<sup>2</sup>

- **NAND Scenario – 10%/year minimum feature decrease, \$1500 cost per 12” wafer**

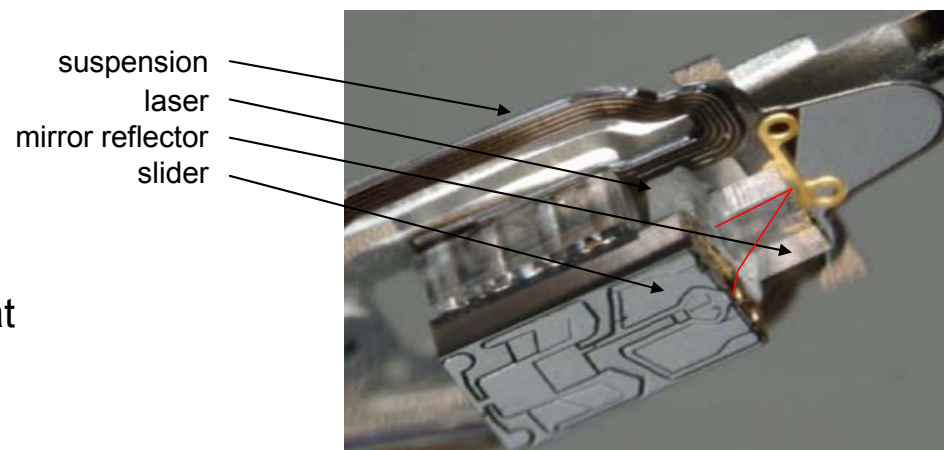
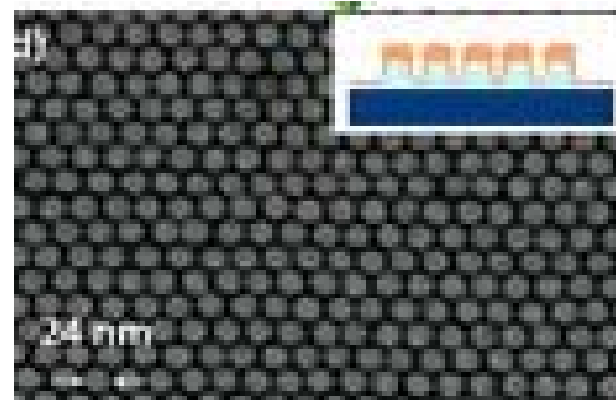
	2010	2011	2013	2015 (?)
Device Capacity	8 GB	8 GB	16 GB	32 GB
Minimum F	25 nm	20 nm	16 nm	12.5 nm
Areal Density	330 Gbit/in <sup>2</sup>	550 Gbit/in <sup>2</sup>	660 Gbit/in <sup>2</sup>	1330 Gbit/in <sup>2</sup>
Devices / 300 mm Wafer	364	522	364	364
TB on 300 mm Wafer	2.9 TB	4.2 TB	5.8 TB	11.2 TB
\$ / GB at Wafer Level	\$0.52	\$0.36	\$0.26	\$0.13

- **What could change? Transition to 3 bit per cell (8 voltage states) design. There is a reason why Intel Micron did not do this at the 25 nm node. 3D options but with larger features.**

- **Platter capacity (GB) for a 3.5” disk ~ 1.2 to 1.4) X areal density system**
  - → 635 Gbit/in<sup>2</sup> areal density supports 750 GB platter
  - → 720 Gbit/in<sup>2</sup> areal density supports 1000 GB platter
- **750 GB platter details**
  - Areal Density (Maximum) → 635 Gbit/in<sup>2</sup>
  - Trackwidth → 74 nm
  - Bit Length → 13.5 nm
  - TPI/BPI → 338 KTPI, 1850 KBPI
  - Minimum Feature F → 37 nm (MR sensor width)
  - Memory Cell Area → 4.0 F<sup>2</sup>
- **Continued 40% annual areal density increases will eventually require minimum features sizes for the MR sensor with smaller dimensions than semiconductor roadmap projections. Fortunately MR sensors are isolated structures.**
- **The HDD Industry is in transition and anticipate density doubling every 5 years, i.e. 18% per year with the eventual introduction of patterned media and / or heat assisted recording**

## HDD Landscape – Two Strategies

- **Media patterning strategies rely on introduction of imprint technology, a semiconductor roadmap strategy for 2014**
  - E-beam lithography at 1X for master stencils
  - Patterning/Planarization/Stencil development and infrastructure → COST and TIME
  - Major system changes to accommodate bit location and shingle writing
  
- **Energy assisted strategies must define trackwidths, ~ 2X MRw, using heat, by adding additional components onto the head slider**
  - New media
  - Thermal reliability for media overcoat and heat transducer
  - Laser supply chain
  
- **Any new technology must be sustainable in the 2.5 Tbit/in<sup>2</sup> environment**



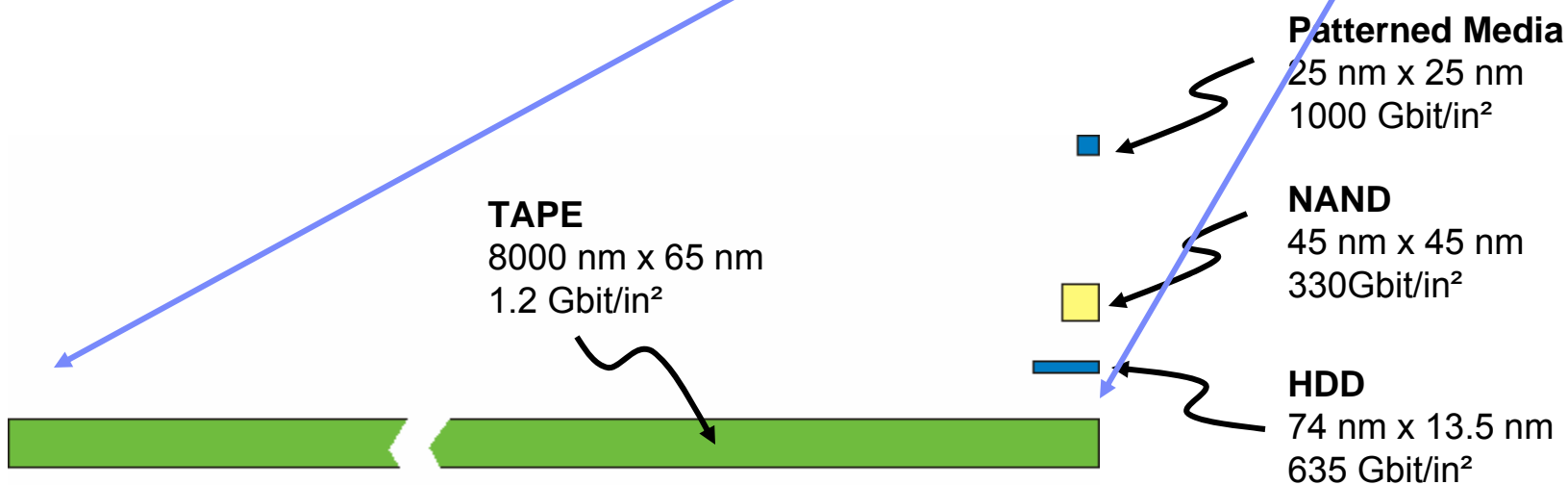
M. Re, "Has HAMR reached a critical mass", The Information Storage Industry Consortium Symposium on Alternative Storage Technologies, April 2009, [www.insic.org](http://www.insic.org)

## Storage Bit Cells and Extendability

- **Scaled Bit Cells**



- **Magnified View of Scaled Bit Cells**





## Areal Density Scenarios relative to 2014

### ▪ HDD

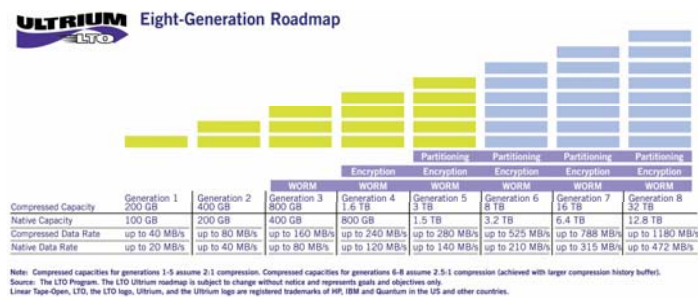
- Conservative: 20% density increases achievable
- Aggressive: 30% density increases are challenging (shingling interim solution)

### ▪ NAND Flash

- Conservative: 20% density increases are achievable given the lithography roadmap strategies project reducing feature size 10% annually
- Aggressive: Sustained 30% density increases are difficult given the conventional understanding of lithography roadmaps and optical processing tooling strategies.

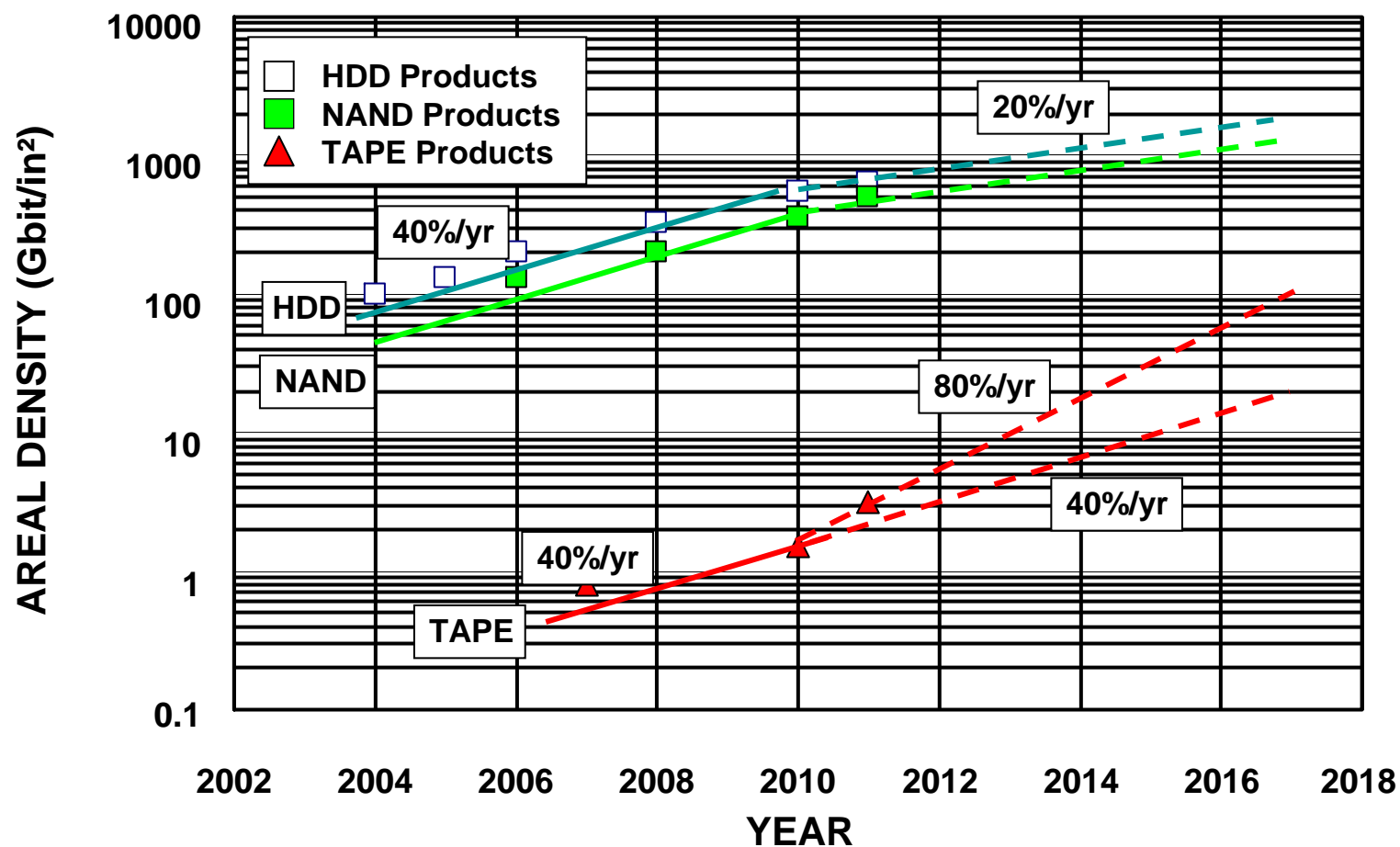
### ▪ TAPE

- Conservative: 40% density increases achievable with anticipation of following the LTO Roadmap presently at Generation 5
- Aggressive: 80% density increases are possible since the needed transducer technology presently exists in the HDD environment but “mechanical” issues related to positioning, wear, and tape stability must be addressed – not NANOSCALE issues



## Annual Areal Density Growth Rate Scenarios

- HDD – Transition to New Technology, Sensor Output, Lithography
- NAND Flash – Lithography and Endurance
- TAPE – No Lithography Issues, Mechanical Realities



## ▪ Density Increases

- Tape → > 40% per year building on HDD **existing** technology, no nano-scale issues
- HDD → 20% per year requiring **revolutionary** technologies
- NAND → 20% per year with evolutionary lithography  
→ > 20 % per year with low endurance multi-bit cells

## ▪ TAPE differences relative to NAND and HDD

- Bit cell is 200X larger → thermal kT fluctuations do not impact endurance / bit stability
- Media thickness is 200X thinner → comparable volumetric densities at component level
- Lithography requirements not dependent on semiconductor roadmap innovations

## ▪ Numbers

- Today's lithographic features are **20 nm**; achieving **16 nm** is difficult for NAND and HDD
- Areal Densities: HDD ~ **730 Gbit/in<sup>2</sup>**, NAND ~ **550 Gbit/in<sup>2</sup>**, TAPE ~ **2 Gbit/in<sup>2</sup>**
- NAND cost is **10X** greater than HDD cost. HDD cost is **2.5X** greater than TAPE cost
- Moore's Law, i.e. capacity doubling per unit area every two years (**40% per year**), will change for NAND and HDD